47. (New) The method according to claim 43, further comprising the step of:

delineating a coil out of the structured surface layer as the at least one passive electronic component.

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48. (New) The method according to claim 47, further comprising the steps of:

in response to an undercut of the coil, measuring a resonance frequency of an oscillating circuit formed on the basis of the coil; and

determining from the resonance frequency the extent of the lateral undercut.

In The Abstract:

Delete the Abstract and insert:

--Abstract Of The Disclosure

A device and a method for determining the extent of an at least locally lateral undercut of a structured surface layer on a sacrificial layer. The structured surface layer for this purpose locally has at least one passive electronic component, using which a physical measured quantity can be determined, which is proportional to the extent of the lateral undercut. The method for generating this device proposes, initially on the structured surface layer in a first etching method, to provide the surface layer at least locally with a structuring having trenches and, in a second etching method, proceeding from the trenches, to undertake at least locally a lateral undercut of the structured surface layer. In this context, in the first etching method on the surface layer, locally at least one passive electronic component is additionally delineated out, which in response to a subsequent undercutting of the surface layer is also undercut. The physical measured quantity is determined without contact, preferably by sending an electromagnetic emission into the passive component.--.

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Remarks

This Preliminary Amendment cancels original claims 1-22, without prejudice, in the underlying PCT Application No. PCT/DE00/00749. This Preliminary Amendment also adds new claims 23-48. The new claims do not add new matter to the application, but do conform the claims to U.S. Patent and Trademark Office rules.

The amendments to the specification and abstract are to conform the